


EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	23	SCHWARM-ALEXANDER-T SCHWARM-A-T	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/22 17:55
S2	31	APPLIED-MATERIALS-INC and (DOE or "design of experiments" or "designed experiments")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/22 18:09
S3	8651	DOE or "design of experiments"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/22 18:09
S4	9231	DOE or "design of experiments" or "designed experiments"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/25 00:34
S5	3168	(DOE or "design of experiments" or "designed experiments") and model\$6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/22 19:43
S6	1718	(DOE or "design of experiments" or "designed experiments") and model\$6 and automat\$6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/22 19:43
S7	337	(DOE or "design of experiments" or "designed experiments") same model\$6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/22 19:52
S8	91	((DOE or "design of experiments" or "designed experiments") same model\$6) and (semiconductor or wafer)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/22 19:46
S9	21	(DOE or "design of experiments" or "designed experiments") same model\$6 same automat\$6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/22 19:52

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S10	6	(DOE or "design of experiments" or "designed experiments") with (import or imported or importing)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/24 22:21
S11	2240	((import or imported or importing) near (data or experiments))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/24 20:57
S12	2	((import or imported or importing) near (data or experiments)) same (DOE or "design of experiments" or "designed experiments")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/24 21:02
S13	14	(DOE or "design of experiments" or "designed experiments") same (import or imported or importing)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/24 21:58
S14	14	"design-expert"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/24 22:23
S15	1	(import or importing or imported) with experiment with design	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/24 22:24
S16	1	(import or importing or imported) with experiment with external	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/24 22:25
S17	35	(DOE or "design of experiments" or "designed experiments") and (import\$6 near2 model)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/24 23:16
S18	9	(DOE or "design of experiments" or "designed experiments") and (import\$6 near model)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/24 23:19

EAST Search History

S19	26	((DOE or "design of experiments" or "designed experiments") and (import\$6 near2 model)) not ((DOE or "design of experiments" or "designed experiments") and (import\$6 near model))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/24 23:41
S20	1159	703/2.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/24 23:41
S21	212	703/2.ccls. and experiment	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/24 23:42
S22	1960	700/29,31,108,109.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/24 23:42
S23	163	700/29,31,108,109.ccls. and experiment	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/24 23:43
S24	361	(DOE or "design of experiments" or "designed experiments") and (import or imported or importing)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/25 00:35
S25	253	(DOE or "design of experiments" or "designed experiments") and (import or imported or importing) and model\$8	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/25 00:36
S26	256	(DOE or "design of experiments" or "designed experiments") and (import or imported or importing) and (model\$8 or "transfer function")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/25 00:37
S28	6110	("edge time" or "center time" or "baseline time")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/22 17:59

EAST Search History

S29	21	("edge time" or "center time" or "baseline time") and (CMP or (chemical with mechanical with planarization))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/22 18:05
S30	728	(time near2 (recipe or input)) and (CMP or (chemical with mechanical with planarization))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/22 18:06
S31	314	(time near (recipe or input)) and (CMP or (chemical with mechanical with planarization))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/22 18:06
S32	28	(time near (recipe or input)) same (CMP or (chemical with mechanical with planarization))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/22 18:06
S33	13298	(DOE or (design near experiment))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/16 20:35
S34	199	(DOE or (design near experiment)) and (time near scal\$6)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/16 20:36
S35	199	(DOE or (design near experiment)) and ((time near scal\$6) or time-scal\$5)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/16 20:36
S36	64	(DOE or (design near experiment)) and ((time near scal\$6) or time-scal\$5) and (semiconductor or wafer)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/16 21:53
S37	85	(DOE or (design\$5 near experiment)) and ((time near scal\$6) or time-scal\$5) and (semiconductor or wafer)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/16 23:00
S38	39	STAT-EASE	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/16 22:33

EAST Search History

S39	4	("20030055541" "20030090382" "20030128122" "20040021581").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/05/16 22:51
S40	0	((("design of experiment")))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/16 23:01
S41	0	((("design of experiments")))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/16 23:01
S42	0	("design of experiments")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/16 23:01
S43	0	"design of experiments"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/16 23:01
S44	1887	design adj experiments	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/16 23:24
S45	2	(design adj experiments) same ((time near scal\$6) or time-scal\$5)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/16 23:02
S46	44	(design adj experiments) and ((time near scal\$6) or time-scal\$5)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/16 23:02
S47	18	S46 not S37	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/16 23:02
S48	104	(design adj experiments) and lineariz\$7	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 15:07

EAST Search History

S49	1	(design adj experiments) and (remov\$5 near3 (nonlinear\$6 or non-linear\$6))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/16 23:25
S50	32	SCHWARM-ALEXANDER-T SCHWARM-A-T	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 13:54
S53	789	lineariz\$7 with scal\$5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 14:00
S54	4	(lineariz\$ with scal\$5) and (DOE or (design near experiment\$5))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 14:08
S55	16	(lineariz\$ with tim\$5) and (DOE or (design near experiment\$5))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 14:11
S56	73	"center time" and "edge time"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 14:38
S57	98	("6381564" "6604092" "6816867" "5793965" "6292830" "6944508" "6044212" "6175816" "6389379" "5862364" "6049822" "6393434" "5490097" "5828575" "6185476" "6219586" "6219586" "6360188" "6415196" "7027970" "4597726" "7020844" "5314017" "5380443" "5401300" "5407466" "5407467" "5556449" "5558698" "5781430" "5933348" "6012330" "6546522" "6725183" "6799078" "6983233" "5343517" "6063127" "5284069" "5447466" "5547028" "5720342" "5730217" "6302005" "6720519" "6875695" "6998196" "6115722" "5619685" "5710900").pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 14:39

EAST Search History

S58	111	(design near experiments) and lineariz\$7	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 15:08
S59	587	scal\$5 same lineariz\$7 same time	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 15:08
S60	219	(scal\$5 same lineariz\$7 same time) and (DOE or experiment)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 15:09
S61	288	(scal\$5 same lineariz\$7 same time) and (DOE or experiment\$5)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 15:10
S62	25	(scal\$5 same lineariz\$7 same time) and (DOE or (design\$4 near3 experiment\$5))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 15:10
S63	4148	(DOE or (design\$4 near2 experiment\$5)) and (wafer or semiconductor)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 15:11
S64	3130	(DOE or (design\$4 near2 experiment\$5)) and (wafer or semiconductor) and (factor or response)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 15:11
S65	2759	(DOE or (design\$4 near experiment\$5)) and (wafer or semiconductor) and (factor or response)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 15:11
S66	1550	((design\$4 near experiment\$5)) and (wafer or semiconductor) and (factor or response)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 15:11
S67	1029	((design\$4 near experiment\$5)) and (wafer or semiconductor) and (factor or response) and (lineariz\$8 or scal\$5)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 15:12

EAST Search History

S68	1029	(design\$4 near experiment\$5) and (wafer or semiconductor) and (factor or response) and (lineariz\$8 or scal\$5)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 15:12
S69	42	((design\$4 near experiment\$5) same (lineariz\$8 or scal\$5)) and (wafer or semiconductor) and (factor or response)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 15:25
S71	913	(DOE or "design of experiments").ab, ti.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 15:26
S72	38	(DOE or "design of experiments").ab, ti. and (lineariz\$6 or scal\$6)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 15:29
S73	0	("design of experiments").ab,ti. and (lineariz\$6 or scal\$6)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 15:30
S76	13	(design adj experiment).ab,ti. and (lineariz\$6 or scal\$6)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 15:32
S77	10	(design adj experiment).ab,ti. and factor and response	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 15:32
S78	29	((design adj experiment) or DOE).ab, ti. and factor and response	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 15:36
S79	25	((design adj experiment) or DOE).ab, ti. and interaction	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 15:36